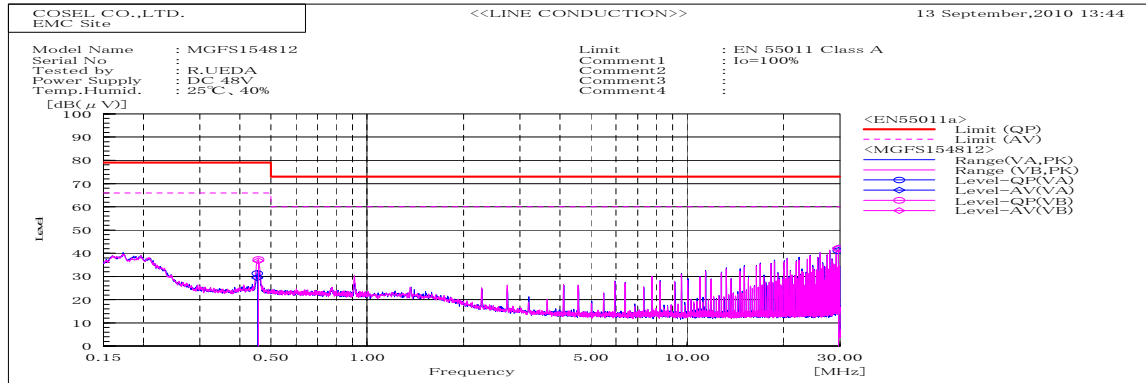
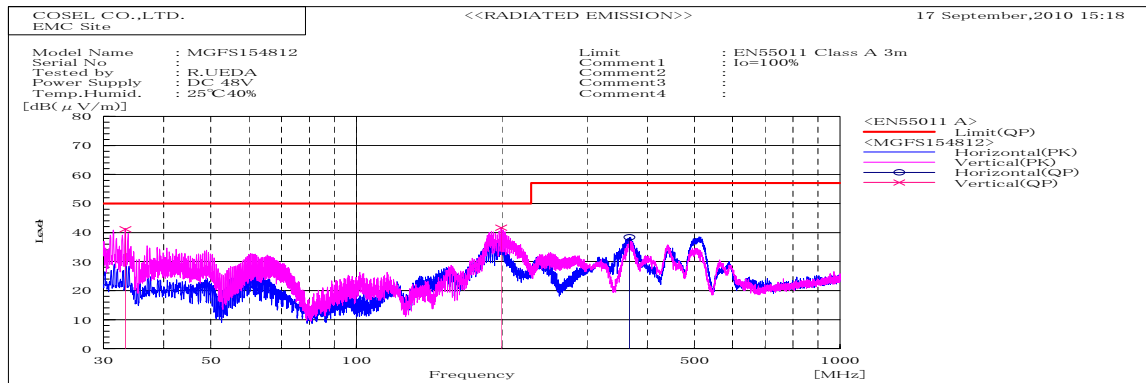


DATA SHEET		Date	21-Sep-10
Model	MGFS154812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45346		VA	21.2	19.3	10.1	31.3	29.4	79	66	47.7	36.6	Pass	
0.45705		VB	27.3	26.6	10	37.3	36.6	79	66	41.7	29.4	Pass	
29.65455		VB	30.9	31.1	11	41.9	42.1	73	60	31.1	17.9	Pass	
29.66275		VA	30.5	31.6	10.6	41.1	42.2	73	60	31.9	17.8	Pass	

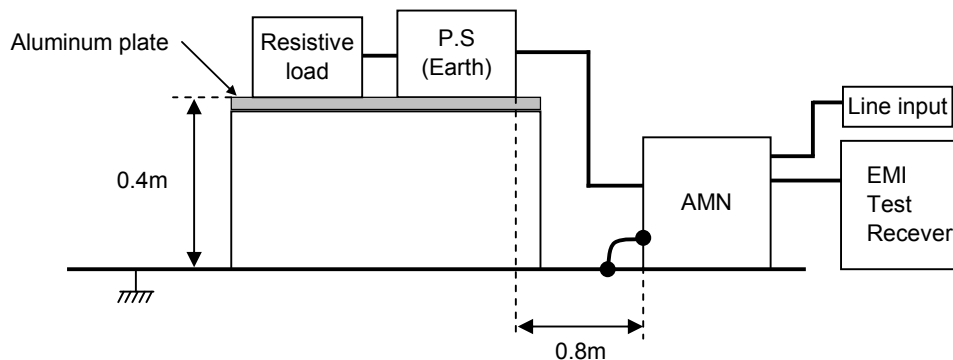


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
33.29	V	Stable	56.2	-15.1		41.1	50	8.9	Pass	100	13	
199.236	V	Stable	63.7	-22		41.7	50	8.3	Pass	114	231	
366.826	H	Stable	54.1	-15.7		38.4	57	18.6	Pass	110	184	

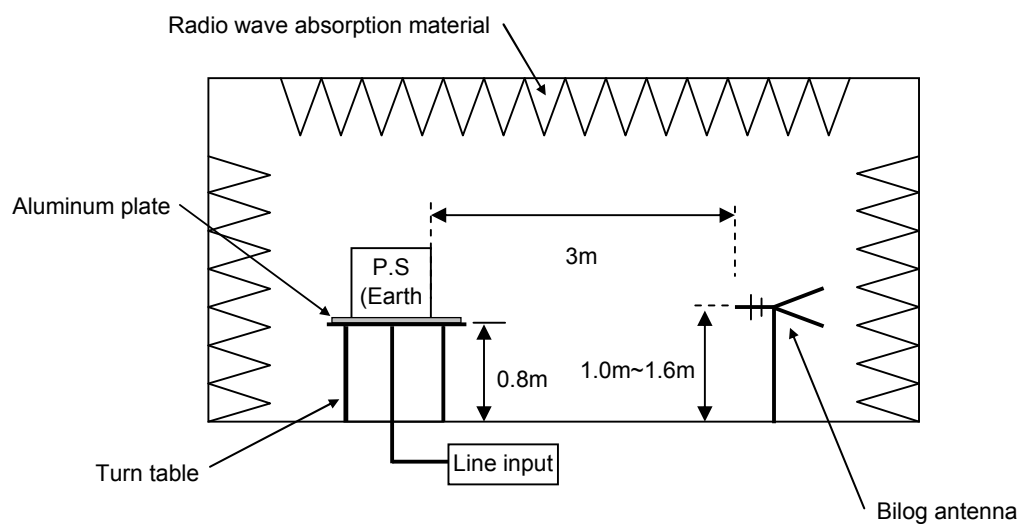
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

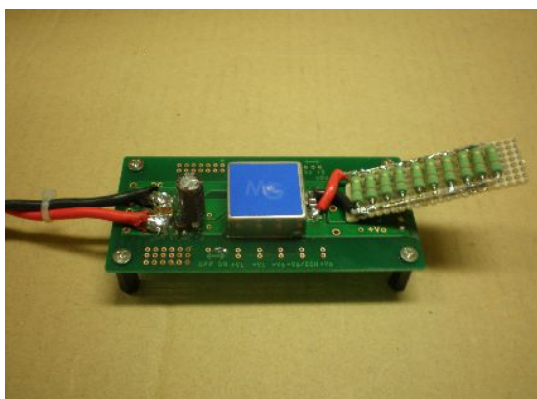


Conditions

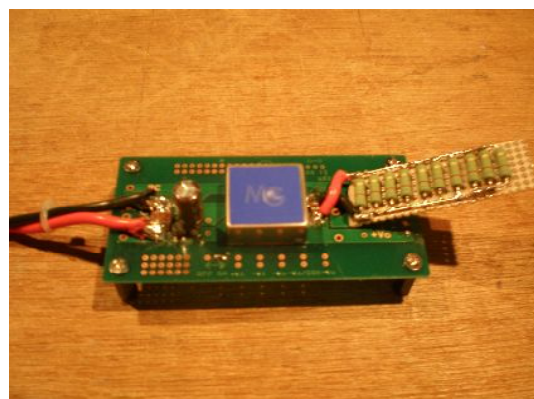
Test : EMI
Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

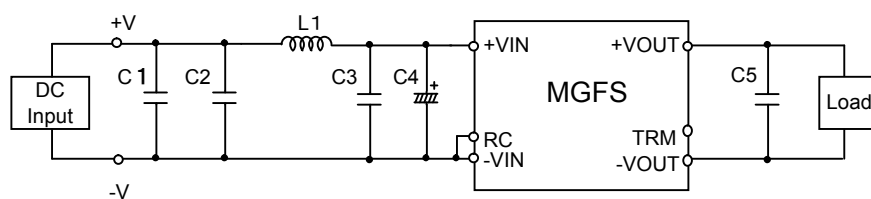


Fig.1 Testing circuitry 1

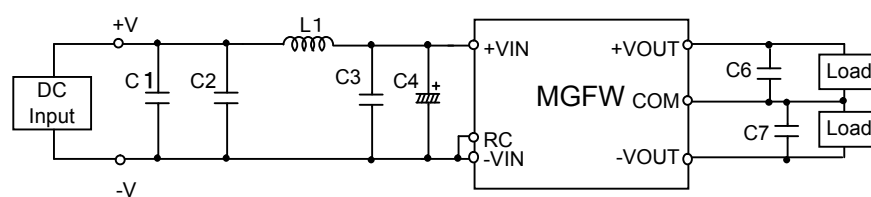


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)